Notice of References Cited

Application/Control No. Applicant(s)/Patent Under Reexamination 10/538,270 YAMASHITA ET AL. Examiner Art Unit Page 1 of 1 Kris Mittal 4115

U.S. PATENT DOCUMENTS

	U.S. I AILEN DOCUMENTO						
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification		
*	А	US-2002/0062250	05-2002	Nagano et al.	705/14		
*	В	US-2004/0221018	11-2004	Ji, Eun-Mook	709/217		
*	С	US-2002/0019774	02-2002	Kanter, Andrew S.	705/14		
*	D	US-2004/0003396	01-2004	Babu, Suresh P.	725/34		
*	Е	US-7,043,526	05-2006	Wolfe, Mark A.	709/203		
*	F	US-6,466,967	10-2002	Landsman et al.	709/203		
*	G	US-6,336,131	01-2002	Wolfe, Mark A.	709/203		
*	Н	US-6,411,992	06-2002	Srinivasan et al.	709/218		
	1	US-					
	J	US-					
	к	US-					
	L	US-					
	м	US-					

FOREIGN PATENT DOCUMENTS

	FOREIGN PATENT DOCUMENTS								
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification			
	N								
	0								
	Р								
	Q								
	R								
	s								
	Т								

NON DATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
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	v						
	w						
	x						

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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